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| Notice of References Cited | Application/Control No. 10/666,669 | Applicant(s)/Patent Under Reexamination TUAN ET AL. | |
| | Examiner Daniel D. Chang | Art Unit 2819 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| | A | US-2003/0218478 A1 | 11-2003 | Sani et al. | 326/33 |
| | B | US-6,208,171 B1 | 03-2001 | Kumagai et al. | 326/121 |
| | C | US-6,169,419 B1 | 01-2001 | De et al. | 326/58 |
| | D | US-5,583,457 A | 12-1996 | Horiguchi et al. | 326/121 |
| | E | US-5,801,548 | 09-1998 | Lee et al. | 326/44 |
| | F | US-5,958,026 A | 09-1999 | Goetting et al. | 710/52 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
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| | P | | | | | |
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| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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